## Notice of References Cited Application/Control No. 10/049,212 Examiner Vivian Chen Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,322,923	11-2001	Spotnitz et al.	429/144
	В	US-5,273,657	12-1993	Nakashima et al.	210/640
	С	US-5,514,461	05-1996	Meguro et al.	428/310.5
	D	US-4,863,604	09-1989	Lo et al.	210/490
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

* .		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					·
	Φ					
	σ					
	R	-				
	Ø					
	Т	•				

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	>						
	w						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.